

## SPECIFICATION AND PERFORMANCE

Series	120C-605D00	File	120C-605D00_Spec	Date	2017/03/02
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## Scope:

This specification covers the requirements for product performance, test methods and quality assurance provisions of 120C-605D00

## **Performance and Descriptions:**

The product is designed to meet the electrical, mechanical and environmental performance requirements specification. Unless otherwise specified, all tests are performed at ambient environmental conditions.

## **RoHS**:

All material in according with the RoHS environment related substances list controlled.

MATERIAL AND FINISH							
INSULATOR	Material	LCP UL94V-0, Black					
CONTACT	Material	Phosphor Bronze C5210, 0.2t Hold down: Brass, C2680, 0.2t					
CONTACT	Plating	10u" Gold plating on contact area, Tin plating on solder area Hold down: Tin plating					
SHELL OR COVER	Material	Stainless Steel, SUS304, 0.2t					
SHELL OR COVER	Plating						
RATING	Voltage Rating: 30VAC Current Rating: 1.5A Temperature Rating: -40°C to +85°C						

ELECTRICAL						
Item	Requirement	Test Condition				
Contact Resistance	$30m\Omega$ max.(initial) ΔR=15mΩ max.	Subject mated contacts assembled in housing to 20 mV max. open circuit at 10mA.				
Dielectric Withstanding Voltage	No creeping discharge nor Flashover shall occur. Current leakage: 1mA max.	500V for one minute. test between adjacent circuit. EIA364,TP-20				
Insulation Resistance	1000MΩ min, initial 100MΩ min. after test	Impressed voltage 500VDC for one minute, test between adjacent circuit EIA364, TP-21				
Current Rating	30°C max. under loaded rating current 1.5A DC	The contacts shall be wired in series and apply rated current. Measure the temperature rising on contact. IEC512-PT3				

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MECHANICAL						
Item	Requirement	Test Condition				
Connector durability	$30m\Omega$ max, initial ΔR=15mΩ max.	Cycle rate: 400 to 600 cycles per hours No. of cycles: 10,000cycles EIA364, TP-09				
Total Mating Force	28.8N max	Measure the card push in force at 25mm/min. EIA364,TP-29				
Total Unmating Force	3.7N min.	Measure the card extraction force at 25mm/min. EIA364,TP-13				
Card Reverse Insertion	No electrical connection and Physical damage to connector. 43.2 N Min. Mating force.	Test speed: 25mm/min. Mating device: Normal CFast card. Reference: EIA364,TP-3				
Solderability	Solder Coverage: 95% Min.	Solder Temperature: 245±3°C Immersion Duration: 5±0.5sec. Solderability Test Method, Condition C JESD22-B102D				

ENVIRONMENTAL							
Item	Requirement	Test Condition					
Humidity	1,000MΩ (Initial)	Ambient Temp.: 40±2°C					
	100MΩ (After Test)	R. H.: 90 to 95%,					
	$30m\Omega$ max. (Initial)	Duration: 96hrs, D/C engaged.					
	$\Delta R = 15 m\Omega$ max.	EIA364, TP-31 Method II, Condition A,					
Thermal Shock	1,000MΩ (Initial)	Temp. Range: -40 to 85°C					
	100MΩ (After Test)	No. of Cycles: 5 cycles for 60 minutes					
	$30m\Omega$ max. (Initial)	Dummy card engaged during test					
	$\Delta R = 15 m\Omega$ max.	EIA364,TP-32					
Physical Shock	No electrical discontinuity	Accelerated Velocity: 50G (490s/m)					
	greater than 100n sec. shall	Waveform : Semi-Sine					
	occur.	Duration : 11m sec.					
	$30m\Omega$ max. (Initial)	No of Shocks: 3/dir., 3 axis, (18 in total),					
	$\Delta R = 15 m\Omega$ max.	EIA364, TP-27					
Vibration (Low	No electrical discontinuity	Frequency Range: 10-55-10					
Frequency)	greater than 100n sec. shall	Total Amplitude: 1.52mm pp or 98.1m/s					
	occur.	Duration: 2hrs three axes (6hrs in total)					
	$30m\Omega$ max. (Initial)	EIA364,TP-28					
	$\Delta R = 15 m\Omega$ max.						
Temperature Life	$30m\Omega$ max. (Initial)	Chamber Temperature: 85±3°C					
	$\Delta R = 15 m\Omega$ max.	Duration: 250 hours					
		Dummy card engaged during test					
	-	EIA364,TP-17					
Salt Spray	30mΩ max. (Initial)	Atmosphere: salt spray from 5% solution length					
	$\Delta R = 15 m \Omega$ max.	of test 48hours exposure					
	Visual: no damage	Temperature: 35±0.5°C					
		No engagement during the test, EIA364, TP-26B					

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		Test Group								
Test Items	Α	В	С	D	Е	F	G	н	1	
	Test Sequence									
Examination of The Product	1,5	1,5	1,6	1,8	1,7	1,7	1,7	1,3	1,3	
Low Level Contact Resistance	2,4		2,5	2,4,6			4,6			
Dielectric Withstanding Voltage					3,6	3,6				
Insulation Resistance					2,5	2,5				
Current Rating				7						
Total Mating Force		2								
Total Unmating Force		3								
Durability	3						2			
Card Reverse Insertion		4								
Vibration			4							
Mechanical Shock			3							
Temperature Life				3						
Reseating				5			5			
Humidity					4					
Thermal Shock						4				
Salt Spray							3			
Solderability								2		
Resistance to Reflow Soldering Heat									2	